Search Notes				
	18 94 1898 USA			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/736,680	CHANG ET AL.	
Examiner	Art Unit	
Shick C. Hom	2666	

SEARCHED				
Class	Subclass	Date	Examiner	
370	230, 235, 357, 359, 360, 362,	2/15/2006	SH	
370	372, 373,	2/15/2006	SH	
370	386, 419,	2/15/2006	SH	
370	422	2/15/2006	SH	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEAR (INCLUDING S	CH NOTES EARCH STRATEGY)
	DATE	EXMR
East search	2/15/2006	SH
inventor search	2/15/2006	SH